Silicon Microfabrication Part 2 – Deposition & Wet Etching



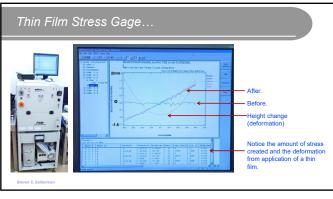


Thin Films • Thermal Silicon Oxide Thermal Silicon Oxide Amorphous material. Insulating layer. Mask Sacrificial layer. Impurities such as Na⁺ and K⁺ diffuse through it. Most dopants except Ga diffuse poorly through it. Thicknesses usually less than 1 µm are produced. Silicon Dioxide (SiO₂) by CVD Insulator between conducting layers. Diffusion and ion implantation masks. Sacrificial material.



- Chemical Vapor Deposition (deposition of a solid on a heated surface from a chemical reaction in the vapor phase.)

- Polysilicon Films (high-purity form of silicon with many silicon atoms)
 Initially amorphous but may crystallize during deposition.
 Transition from small grains at the film/substrate interface to columnar crystallites on top.
 Dopants, impurities and temperature influence crystal orientation.
 Dopants decrease resistivity to produce conductors and control stress.
 Con bo depend by diffusion implantation or by the addition of
 - Can be doped by diffusion, implantation, or by the addition of dopant gases during deposition.
 - Piezoresistive sensor elements may be fabricated from polysilicon.
 - Low Pressure Chemical Vapor Deposition (LPCVD).



• Silicon Nitride (Si₃N₄)

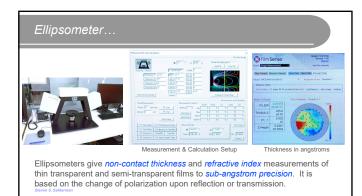
- Amorphous
- Insulator between conducting layers.
- Excellent water and ionic barrier.
- Can not be directly put on silicon.
- May be put on a silicon dioxide layer.
- Highly selective etch rates.
- Hard material that may be used for structural purposes.
- Useful in high temperature applications.
- An important mechanical membrane and isolation/buffer material.
- CVD Techniques

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• Phosphosilicate Glass (PSG)

- PSG and borophosphosilicate glasses (BPSG) soften and flow at lower temperatures, enabling smoothing of topography.
- Etch faster than silicon dioxide, hence more suitable sacrificial layer.
- Dielectric between conducting metal layers.
- · Gettering (absorbing) of alkali ions and flow capabilities.
- Passivation coat to provide mechanical protection
- Creating by addition of phosphine to the gas steam.



Metal Films

- Aluminum and tungsten are commonly used.
- Metals with high reflectivity include Al (aluminum) and Au (gold).

- Metals with high reflectivity include AI (aluminum) and Au (gold)
 Metals with high mass density include W (tungsten), Au (gold) and Pt (platinum).
 Metals with specific adsorption and adhesion characteristics include Pd (palladium), Ir (iridium), Au (gold) and Pt (platinum).
 Tungsten will nucleate on silicon or metal surfaces, but not on dielectrics such as oxides and nitrides.
- CVD and PVD (Physical Vapor Deposition) techniques.

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Thin-Film Deposition Processes

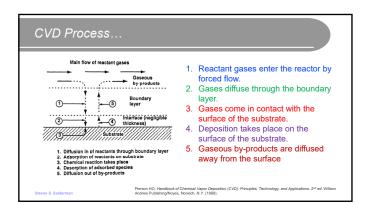
- **Chemical Vapor Deposition** 1.
 - Chemical vapor beposition is the deposition of a solid on a heated surface from a chemical reaction in the vapor phase.
 Physical Vapor Deposition
 Material is transported in vapor form from a source to a substrate through a vacuum or low-pressure gaseous environment:
 Every supervision
- 2.

 - - Evaporation,
 Sputtering,
 Arc vapor deposition
 Laser ablation,
- Ion plating.
 S. Epitaxial Deposition
 A single crystal layer can be deposited onto the surface of a substrate water.

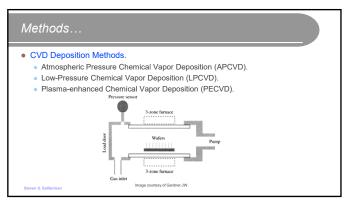
Chemical Vapor Deposition (CVD)

- Chemical vapor deposition is the deposition of a solid on a heated surface from a chemical reaction in the vapor phase.
- Like PVD, the deposition species are atoms or molecules or a combination of these.
- Advantages:
 Advantages:
 High throwing power for ease of filling deep recesses, holes and other three-dimensional shapes;
 Deposition is not limited to line-of-sight;
 Coatings up to several centimeters can be realized;
 Ultrahigh vacuums are not necessary; and
 Co-deposition of elements or compounds is achievable
- Disadvantages

 - Use of temperatures above 600°C, Requirement for chemical precursors with high vapor pressure and toxicity, Toxic by-products.







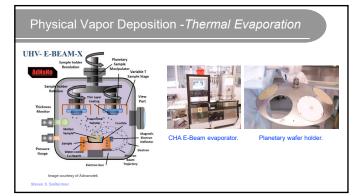


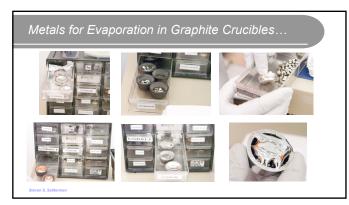


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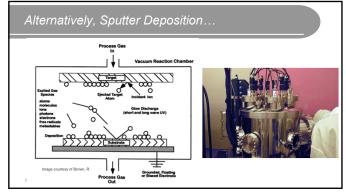
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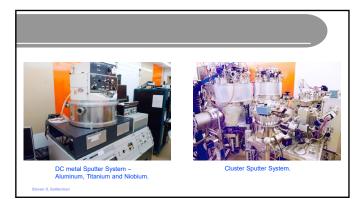












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Some Example Select Thin-Films

- SiO₂ can be deposited with CVD by reacting silane and oxygen in a LPCVD reactor as shown: SiH₄ + O₂ $\xrightarrow{500^{\circ}C}$ SiO₂+ 2H₂
- SiO₂ can be deposited with LPCVD by decomposing tetra-ethyl-ortho-silicate, Si(OC₂H₅)₄, also known as TEOS. This is vaporized from a liquid source.



$\mathrm{SiCl}_{2}\mathrm{H}_{2} + 2\mathrm{H}_{2}\mathbf{0} \xrightarrow{900^{\circ}C} \mathrm{SiO}_{2} + 2\mathrm{H}_{2} + 2\mathrm{HCl}$

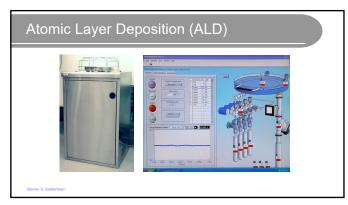
• Si₃N₄ can be deposited with LPCVD using dichlorosilane and ammonia:

$$3SiCl_2H_2 + 4NH_3 \xrightarrow{800\%} Si_3N_4 + 6HCL + 6H_2$$

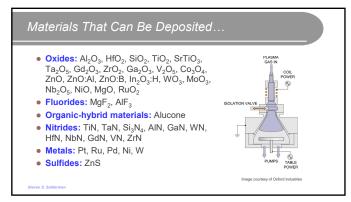
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CVD Thin-Film Properties...

- There are three factors that control the nature and properties of the deposit:
 - Epitaxy
 - Gas-phase precipitationThermal expansion
- CVD structure can be controlled by manipulation of temperature, pressure, supersaturation and the CVD reaction.
- \bullet Ceramics, including SiO_2, Al_2O_3, Si_3N_4 and most dielectrics are amorphous.
- Metal deposits tend to be crystalline.







Select ALD Features...

- 100% film density guarantees ideal material properties.
 Insensitive to dust (grows
- underneath dust!).
- Oxides, nitrides, metals, semiconductors possible (Cambridge Nanotech provides standard recipes).
 Amorphous or crystalline depending on substrate and temperature.



Cambridge NanoTech Inc.

Cambridge NanoTech Inc

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ALD Features...

- Digital thickness control to atomic level (no rate monitor needed, just set the number of atomic layers).
- Perfect 3D conformality, 100% step coverage: uniform coatings on flat, inside porous and around particle samples.
- Low defect density.
- Gentle deposition process for sensitive substrates, no plasma.
- Low temperature deposition possible (RT-400C).
- Low stress because of molecular self assembly.

Ion Implantation

- In ion implantation, the dopant element is ionized, accelerated to a kinetic energy of several hundred keV, and then driven into the substrate.
- The electrical conductivity of an intrinsic semiconductor can be increased through doping. The charge carrier density can be increased through impurities of either higher or lower valence.
- Doping can be used to control etching by reducing etch rates.
 Sources for *n*-type doping include antimony, arsenic and
- Sources for *n*-type doping include antimony, arsenic and phosphorous; and for *p*-type doping, boron.

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Controlled Etching with Chemicals

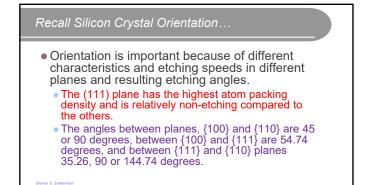
- Anisotropic etchants (potassium hydroxide, ethylene diamine pyrochatechol, and tetramethyl ammonium hydroxide):
 - Etch silicon preferentially along preferred crystallographic directions.
 - Show a reduction of etch rate in heavily doped *p*-type regions.
- Boron typically is incorporated using ion implantation for this purpose.

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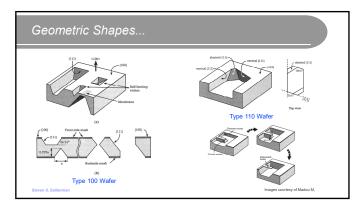
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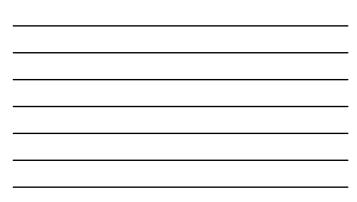
Wet Bulk Surface Micromachining

- In wet bulk micromachining features are sculptured in bulk materials like silicon, quartz, sapphire, ceramics, SiC, GaAs, InP and Ge by orientation independent (isotropic) or orientation-dependent (anisotropic) wet etchants.
- Integrated circuits typically have aspect ratios of 1-2, while in BioMEMS the ratio may be up to 400.



PR PR	PR PR Silicon
Isotropic Etching	Anisotropic Etching





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Isotropic Etching Agents...
  • Isotropic etchants are usually acidic, and lead to
    rounded features (HNA = HF (hydrofluoric acid) + HNO<sub>3</sub>
    (nitric acid) + CH<sub>3</sub>COOH (acetic acid)):
         Si + HNO_3 + 6HF \rightarrow H_2SiF_6 + HNO_2 + H_2O + H_2
                      (H<sub>2</sub>SiF<sub>6</sub> is water soluble)
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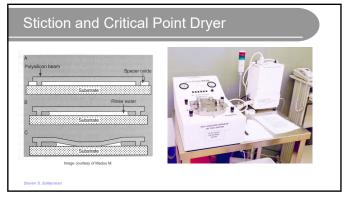
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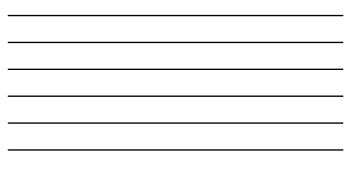
Anisotropic Etching Agents... • Anisotropically etchants are alkaline: $\text{Si} + 2\text{OH}^{-} \rightarrow \text{Si}(\text{OH})_2^{2+} + 4\text{e}^{-}$ $4H_2O + 4e^- \rightarrow 4OH^- + 2H_2$ $Si(OH)_2^{2+} + 4OH^- \rightarrow SiO_2(OH)_2^{2-} + 2H_2O$ \therefore Si + 2OH⁻ + 2H₂O \rightarrow Si(OH)₂²⁺ + 2H₂

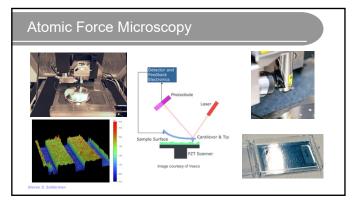


- Common structural elements include polysilicon, polyimide, silicon nitride and tungsten.
 - The polysilicon and its sacrificial layer, silicon dioxide can be applied by LPCVD. Silicon dioxide can be etched away with hydrofluoric acid (HF) solution without etching the polysilicon.

 - Polyimide can be used with aluminum as the sacrificial layer, the latter being dissolvable with acid-based etchants.
 Silicon nitride is both a good structural material and electrical insulator. Polysilicon can be used as the sacrificial layer, in which case KOH and EDP can be used as the etchants.
 Tungsten can be applied by CVD over silicon dioxide, and again HF is a suitable etchant to remove the silicon dioxide sacrificial layer.
 - layer.





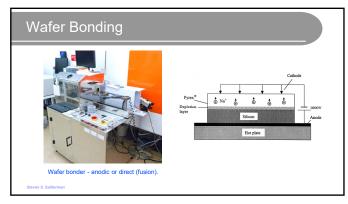


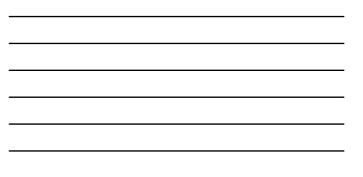
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Substrate Bonding

- 1. Silicon Direct Bonding (or Fusion Bonding)
 - Silicon to Silicon
- Silicon to Silicon
 Silicon on Insulator (SOI)
 No intermediate layers
 Requires heating (450°)
 Anodic Bonding
 Silicon to Glass (Pyrex 7740) Intermediate Adhesive Layers
- 3. Lasers







Summary

- Important thin-films include:

 Thermal Silicon Oxide
 Silicon Dioxide (SiO2)
 Polysilicon

 Silicon Nitride (SisN4)
 Phosphosilicate Glass (PSG)
 Metal films (e.g., tungsten and aluminum)
 Thin films may be produced by:

 Thermal oxidation
 Physical Vapor Deposition
 Chemical Vapor Deposition
 Epitaxial Deposition
 Atomic Layer Deposition (ADL)

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- Ion implantation may be used to improve electrical conductivity or to control etching characteristics.
- Wet bulk micromachining Isotropic and anisotropic etching
 3-D structure and sacrificial layers
- Characterization with Atomic Force Microscopy
- Wafer bonding
 - Silicon direct (or fusion) bonding
- Anodic bonding

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